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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: Takashi FUJITA et al.

Serial Number: Not yet assigned

(§371 of international application No. PCT/JP2004/008711)

Filed: December 19, 2005

For: SPECIFIC COMPONENT MEASURING METHOD BY SPECTRAL

MEASUREMENT

Attorney Docket Number:

053362

Customer Number:

38834

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450 December 19, 2005

Sir:

In compliance with 37 C.F.R. §1.56, Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08. A copy of each non-U.S. document is enclosed herewith.

If there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,

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Enclosure: PTO/SB/08, 1 document and international search report.

Combined Form PTO/SB/08A&B

Sheet

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

of

Complete if Known				
Application Number	New Application - > 0			
Confirmation Number	10/201220			
Filing Date	December 19, 2005			
First Named Inventor	Takashi FUJITA et al.			
Art Unit				
Examiner Name				
Attorney Docket Number	053362			

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.1	Document	Document Number		
		Number	Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		US			

FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No.1	Foreign Patent Document			Publication Date	Name of Patentee or		
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)	MM-DD-YYYY		Applicant of Cited Document	Translation ⁶
		JP	6-18968		03-11-1994	Hitachi, Ltd.	Claims, cited in the ISR	
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NON PATENT LITERATURE DOCUMENTS				
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to indicate here if English language Translation is attached.